



# **4Mb PPI MRAM M-die**

**Parallel Peripheral Interface MRAM**

**3.3V**

• S3R4016V1M

• S3R4008V1M

**Datasheet**

## Feature

- Interface
  - Parallel Asynchronous and Page Mode Interface
- Page Mode Read Access
  - Interpage read access : 70ns
  - Intrapage read access : 15ns
- Page Mode Write Access
  - Interpage write access : 240ns
  - Intrapage write access : 15ns
- Page Size
  - x16 I/O Mode : 4-word page size
  - x8 I/O Mode : 8-word page size
- Low Power Consumption
  - Read current : 12mA
  - Write current : 15mA
  - Standby current : 350uA/235uA
- Data Byte Control(x16 I/O Mode)
  - $\overline{LB}$  : DQ<sub>7</sub>~DQ<sub>0</sub>,  $\overline{UB}$  : DQ<sub>15</sub>~DQ<sub>8</sub>
- Memory cell : STT-MRAM
  - nonvolatile
- Density
  - 4Mb
- Data Integrity : No external ECC required
- Data Endurance
  - Unlimited read cycle
  - 10<sup>14</sup> write cycles
- Data Retention
  - 20 years at 85°C
- Single Power Supply Operation
  - S3R40xxV1M: 2.70V~3.60V
- Operating Temperature Range
  - Industrial Temperature : -40°C to 85°C
- RoHS compliant packages
  - 44TSOP2 (10 mm x 18 mm)
  - 48FBGA (6 mm x 8 mm)

## Performance

Operation	Symbol	Typical Values	Units
Interpage Read Cycle Time	t <sub>RC</sub>	70(Min.)	ns
Intrapage Read Cycle Time	t <sub>PRC</sub>	15(Min.)	ns
Interpage Write Cycle Time	t <sub>WC</sub>	240(Min.)	ns
Intrapage Write Cycle Time	t <sub>PWC</sub>	15(Min.)	ns
Standby Current	I <sub>SB</sub>	235	uA
Interpage Read Current	I <sub>CCR</sub>	12	mA
Intrapage Read Current	I <sub>CCRP</sub>	12	mA
Interpage Write Current	I <sub>CCW</sub>	15	mA
Intrapage Write Current	I <sub>CCWP</sub>	15	mA

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## General Description

The device is a Spin-Transfer-Torque Magneto-resistive Random Access Memory (STT-MRAM). Data is always non-volatile and the device can replace FRAM, low-power SRAM or nvSRAM with same functionality and help to simplify system design. Due to the non-volatility and virtually unlimited endurance characteristics of STT-MRAM, it is suited for code storage, data logging, backup memory and working memory in industrial designs.

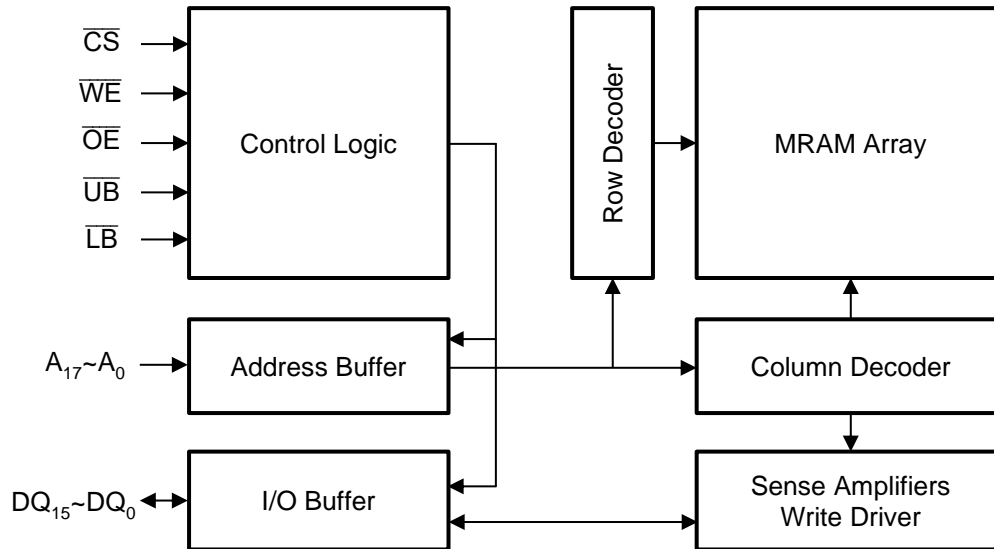
It is offered in density of 4Mbit. It is a fully random-access memory with parallel asynchronous interface. x16 or x8 I/O mode are supported. And x16 I/O mode allows that lower and upper byte access by data byte control ( $\overline{LB}$ ,  $\overline{UB}$ ).

It supports the asynchronous page mode function to enhance the read and write performance. The page size of x16 I/O mode and x8 I/O mode is 4 words and 8 words.

The S3R4016V1M and S3R4008V1M are packaged in industrial standard 44TSOP2 and 48FBGA. These packages are compatible with similar low-power volatile and non-volatile products. The device is offered with industrial (-40°C to 85°C) operating temperature range.

## Pin Description – x16 I/O Mode

**Figure 1 : Functional Block Diagram – x16 I/O mode**



**Table 1 : Pin Description – x16 I/O mode**

Pin	Type	Description
$\overline{CS}$	Input	<b>Chip Select:</b> When $\overline{CS}$ is driven Low, read or write operation are initiated. When $\overline{CS}$ is driven High, the device enters standby mode, and all other input pins are ignored and the output pins are tri-stated. $\overline{CS}$ should be High at power-up to prevent abnormal write operation. This pin does not have internal pullup resistor.
$\overline{WE}$	Input	<b>Write Enable:</b> When $\overline{CS}$ and $\overline{WE}$ are driven Low, write operation is initiated. The rising edge of $\overline{CS}$ causes the device to transfer the data to memory array. The rising edge of $\overline{WE}$ latches the input data. And, the falling edge of $\overline{WE}$ latches a new page address for write cycles.
$\overline{OE}$	Input	<b>Output Enable</b>
$\overline{LB}$	Input	<b>Lower Byte Control:</b> DQ <sub>7</sub> ~DQ <sub>0</sub>
$\overline{UB}$	Input	<b>Upper Byte Control:</b> DQ <sub>15</sub> ~DQ <sub>8</sub>
A <sub>17</sub> ~A <sub>0</sub>	Input	<b>Address</b> The LSB address A <sub>1</sub> ~A <sub>0</sub> are used for page mode read and write operation.
DQ <sub>15</sub> ~DQ <sub>0</sub>	Bidirectional	<b>Data Input/Outputs</b>
V <sub>cc</sub>	Supply	Power pin
V <sub>ss</sub>	Supply	Ground pin
NC	-	Not Connected
DNU	-	Do Not Use : DNUs must be left unconnected.

Pin Description – x8 I/O Mode

Figure 2 : Functional Block Diagram – x8 I/O mode

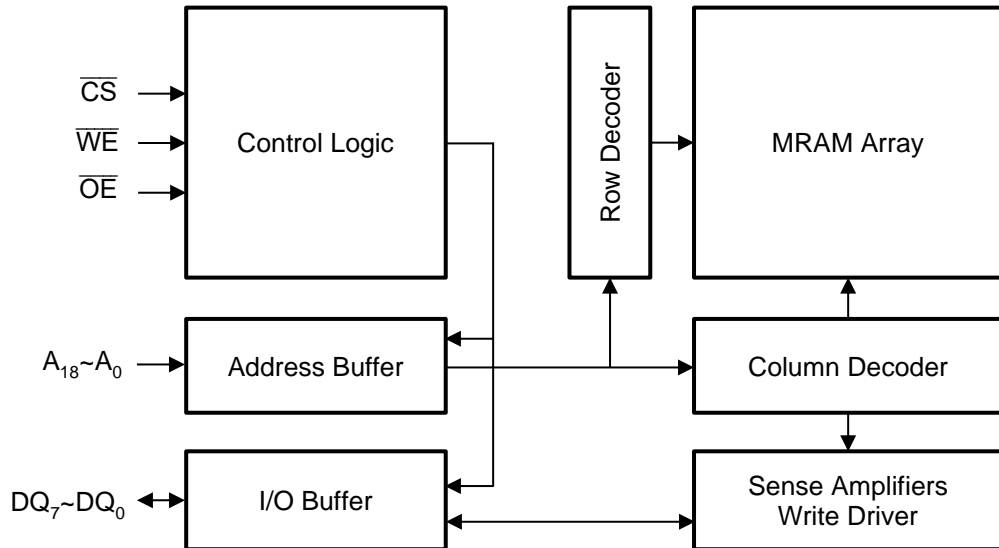


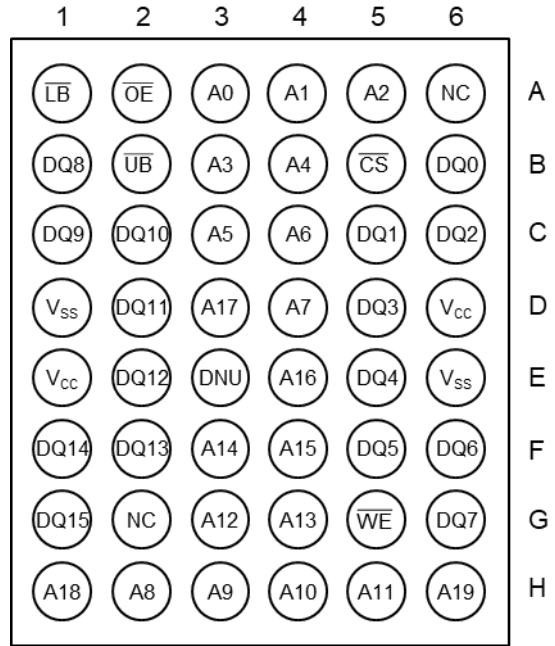
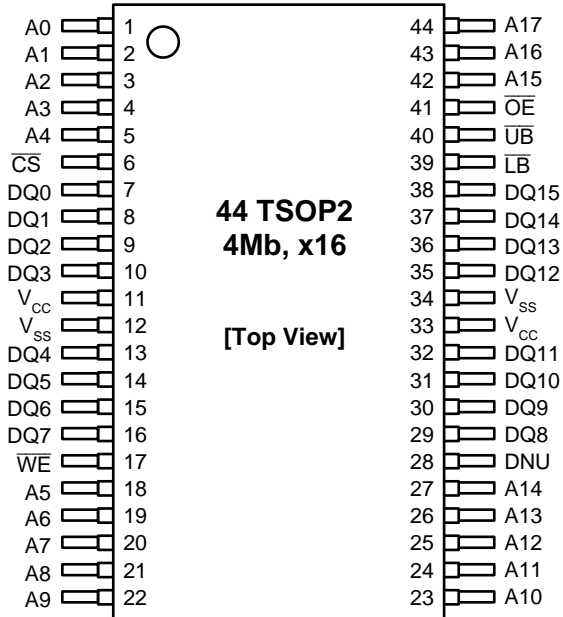
Table 2 : Pin Description – x8 I/O mode

Pin	Type	Description
$\overline{CS}$	Input	<b>Chip Select:</b> When $\overline{CS}$ is driven Low, read or write operation are initiated. When $\overline{CS}$ is driven High, the device enters standby mode, and all other input pins are ignored and the output pins are tri-stated. $\overline{CS}$ should be High at power-up to prevent abnormal write operation. This pin does not have internal pullup resistor.
$\overline{WE}$	Input	<b>Write Enable:</b> When $\overline{CS}$ and $\overline{WE}$ are driven Low, write operation is initiated. The rising edge of $\overline{CS}$ causes the device to transfer the data to memory array. The rising edge of $\overline{WE}$ latches the input data. And, the falling edge of $\overline{WE}$ latches a new page address for write cycles.
$\overline{OE}$	Input	<b>Output Enable</b>
$A_{18}\sim A_0$	Input	<b>Address</b> The LSB address $A_2\sim A_0$ are used for page mode read and write operation.
$DQ_7\sim DQ_0$	Bidirectional	<b>Data Input/Outputs</b>
Vcc	Supply	Power pin
Vss	Supply	Ground pin
NC	-	Not Connected
DNU	-	Do Not Use : DNUs must be left unconnected.

## Package Pin Configuration – x16 I/O Mode

### 48 Ball FBGA(4Mb, x16)

[Top View]

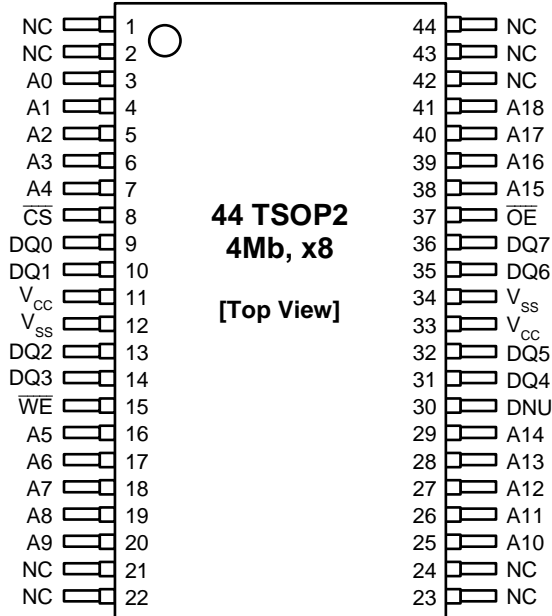


**Table 3 : DNU Pin Description – x16 I/O mode**

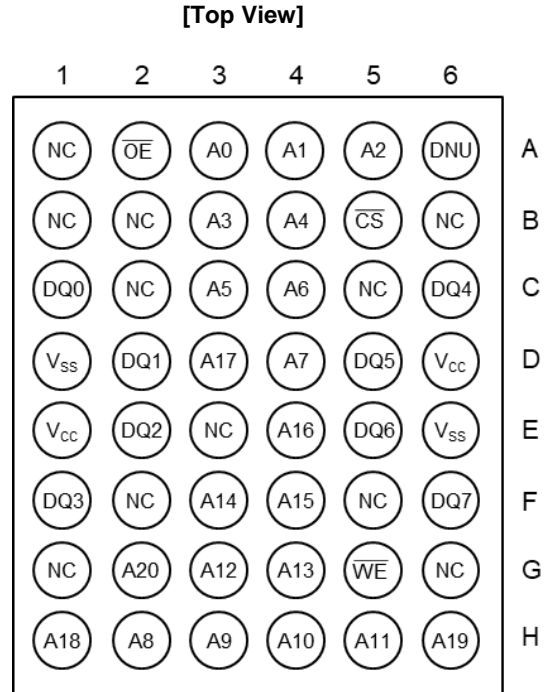
Package	Density	Part Number	DNU pin
44 TSOP2	4Mb	S3R4016V1M	#28
48 FBGA	4Mb	S3R4016V1M	E3



## Package Pin Configuration – x8 I/O Mode



### 48 Ball FBGA(4Mb, x8)



**Table 4 : DNU Pin Description – x8 I/O mode**

Package	Density	Part Number	DNU pin
44 TSOP2	4Mb	S3R4008V1M	#30
48 FBGA	4Mb	S3R4008V1M	A6

## Functional Description

### Functional Description – x16 I/O Mode

**Table 5 : Functional Description - x16 I/O mode**

CS	WE	OE	LB	UB	DQ <sub>7</sub> ~DQ <sub>0</sub>	DQ <sub>15</sub> ~DQ <sub>8</sub>	Modes	Supply Current
H	X	X	X	X	High-Z	High-Z	Not Selected	I <sub>SB</sub>
L	H	H	X	X	High-Z	High-Z	Output disable	I <sub>CCR</sub>
L	H	L	H	H	High-Z	High-Z	Output disable	I <sub>CCR</sub>
L	H	L	L	H	Dout	High-Z	Lower Byte Read	I <sub>CCR</sub>
L	H	L	H	L	High-Z	Dout	Upper Byte Read	I <sub>CCR</sub>
L	H	L	L	L	Dout	Dout	Word Read	I <sub>CCR</sub>
L	L	X	H	H	High-Z	High-Z	Input disable	I <sub>CCW</sub>
L	L	X	L	H	Din	High-Z	Lower Byte Write	I <sub>CCW</sub>
L	L	X	H	L	High-Z	Din	Upper Byte Write	I <sub>CCW</sub>
L	L	X	L	L	Din	Din	Word Write	I <sub>CCW</sub>

### Functional Description – x8 I/O Mode

**Table 6 : Functional Description - x8 I/O mode**

CS	WE	OE	DQ <sub>7</sub> ~DQ <sub>0</sub>	Modes	Supply Current
H	X	X	High-Z	Not Selected	I <sub>SB</sub>
L	H	H	High-Z	Output disable	I <sub>CCR</sub>
L	H	L	Dout	Word Read	I <sub>CCR</sub>
L	L	X	Din	Word Write	I <sub>CCW</sub>

**Notes:**

1. H = High, L = Low, X = don't care, High-Z : high impedance

### Address Pin

**Table 7 : Address Pin**

Density	Address Pin x16 I/O mode	Address Pin x8 I/O mode
4Mb	A[17:0]	A[18:0]

Parameter	x16 I/O mode	x8 I/O mode
Page Address	A <sub>1</sub> ~A <sub>0</sub>	A <sub>2</sub> ~A <sub>0</sub>

## Electrical Specifications

### Absolute Maximum Ratings

Stresses greater than those listed may cause permanent damage to the device. This is a stress rating only. Exposure to maximum rating for extended periods may adversely affect reliability.

**Table 8 : Absolute Maximum Ratings**

Parameter	Min.	Max.	Units
Voltage on Vcc Supply Relative to VSS	-0.5	3.8	V
Voltage on Any Pin relative to VSS	-0.5	3.8	V
Storage Temperature	-55	150	°C
Operating Ambient Temperature	-40	85	°C
ESD HBM (Human Body Model)	≥  2000 V		V
ESD CDM (Charged Device Model)	≥  500 V		V
Solder Reflow Process	JEDEC J-STD-020 reflow profiles - Peak temperature ≤ 260°C - The time above 255°C ≤ 30 seconds - Reflow cycles ≤ 3 times		

### Endurance, Retention and Magnetic Immunity

**Table 9 : Endurance, Retention and Magnetic Immunity**

Parameter	Conditions	Min.	Max.	Units
Write Endurance	-25°C	10 <sup>14</sup>	-	Cycles/page
Data Retention	85°C	20	-	years
Magnetic Field During Write or Read	-	-	24,000	A/m

### Recommended Operating Conditions

**Table 10 : Recommended Operating Conditions**

Parameter / Condition	Min.	Typ.	Max.	Units
Operating Temperature	-40	25	85	°C
Vcc Supply Voltage	2.7	3.3	3.6	V
Vss Supply Voltage	0.0	0.0	0.0	V

## Pin Capacitance

**Table 11 : Pin Capacitance**

Parameter	Conditions	Typ.	Max.	Units
Input Pin Capacitance	TEMP = 25°C; f = 1 MHz; $V_{IN} = 0V$	-	4	pF
Input/Output Pin Capacitance	TEMP = 25°C; f = 1 MHz; $V_{IO} = 0V$	-	6	pF

\* Capacitance is sampled and not 100% tested

## AC Test Condition

**Table 12 : AC Test Conditions**

Parameter	Value
Input pulse levels	0.0V to $V_{CC}$
Input rise and fall times	1ns/1V
Input and output measurement timing levels	$V_{CC}/2$
Output Load	CL = 30pF

## DC Characteristics

**Table 13 : DC Characteristics**

Parameters	Symbol	Test Conditions	Min	Typ	Max	Unit
Input Leakage Current	$I_{LI}$	$V_{IN} = V_{SS}$ to $V_{CC}$	-2	-	+2	uA
Output Leakage Current	$I_{LO}$	$\overline{CS}=V_{IH}$ or $\overline{OE}=V_{IH}$ or $\overline{WE}=V_{IL}$ $V_{OUT} = V_{SS}$ to $V_{CC}$	-2	-	+2	uA
Read Current	Random	$I_{CCR}$ $V_{CC}(\max)$ , $I_{OUT}=0mA$	-	12	16	mA
	Page mode	$I_{CCRP}$ $V_{CC}(\max)$ , $I_{OUT}=0mA$	-	12	16	mA
Write Current	Random	$I_{CCW}$ $V_{CC}(\max)$	-	15	19	mA
	Page mode	$I_{CCWP}$ $V_{CC}(\max)$	-	15	19	mA
Standby Current	$I_{SB}$	$V_{CC}(\max)$ , $\overline{CS} \geq V_{CC}-0.2V$	-	235	370	uA
Input High Voltage	$V_{IH}$	-	$0.7 \times V_{CC}$	-	$V_{CC}+0.3$	V
Input Low Voltage	$V_{IL}$	-	-0.3	-	$0.2 \times V_{CC}$	V
Output High Voltage	$V_{OH}$	$I_{OH}=-1mA$	2.4	-	-	V
Output Low Voltage	$V_{OL}$	$I_{OL}=2mA$	-	-	0.4	V

## AC Timing Parameters

**Table 14 : Read AC Timing Parameter**

Parameter	Symbol	Min.	Max.	Units
Read Cycle Time (Interpage)	t <sub>RC</sub>	70	-	ns
Page Read Cycle Time (Intrapage)	t <sub>PRC</sub>	15	-	ns
$\overline{CS}$ Read Active Time	t <sub>RCA</sub>	65	-	ns
$\overline{CS}$ Falling to Valid Output Time	t <sub>CO</sub>	-	65	ns
Address Access Time <sup>2)</sup>	t <sub>AA</sub>	-	80	ns
Page Address Access Time	t <sub>PAA</sub>	-	15	ns
$\overline{CS}$ Rising to Output Hold Time	t <sub>COH</sub>	3	-	ns
Address change to Output Hold Time <sup>2)</sup>	t <sub>OH</sub>	30	-	ns
Page address change to Output Hold Time	t <sub>POH</sub>	5	-	ns
$\overline{OE}$ Falling to Valid Output Time	t <sub>OE</sub>	-	15	ns
$\overline{UB}$ , $\overline{LB}$ Falling to Valid Output Time <sup>1)</sup>	t <sub>BA</sub>	-	15	ns
$\overline{CS}$ Rising to High-Z Output Time	t <sub>CHZ</sub>	-	8	ns
$\overline{OE}$ Rising to High-Z Output Time	t <sub>OHZ</sub>	-	8	ns
$\overline{UB}$ , $\overline{LB}$ Rising to High-Z Output Time <sup>1)</sup>	t <sub>BHZ</sub>	-	8	ns
Address Transition to $\overline{CS}$ falling Time <sup>2)</sup>	t <sub>CAS</sub>	0	-	ns
$\overline{CS}$ Rising to Address Transition Time <sup>2)</sup>	t <sub>CAH</sub>	0	-	ns
$\overline{WE}$ Rising to $\overline{CS}$ Falling Time	t <sub>WES</sub>	0	-	ns
$\overline{CS}$ Rising to $\overline{WE}$ Falling Time	t <sub>WEH</sub>	0	-	ns
$\overline{CS}$ High Time for Read End	t <sub>CSDR</sub>	5	-	ns
Address Transition Interval Time	t <sub>AX</sub>	-	5	ns

**Notes:**

1. Those parameters are applied for x16 I/O mode only.
2. Address except for page address

## AC Timing Parameters

**Table 15 : Write AC Timing Parameter**

Parameters	Symbol	Min	Max	Unit
Write Cycle Time (Interpage)	t <sub>WC</sub>	240	-	ns
$\overline{\text{CS}}$ Write Active Time <sup>3)</sup>	t <sub>WCA</sub>	20	-	ns
$\overline{\text{CS}}$ Falling to End of Write Time	t <sub>CW</sub>	20	-	ns
Page Write Cycle Time (Intrapage)	t <sub>PWC</sub>	15	-	ns
$\overline{\text{WE}}$ Falling to End of Write (invalid output does not appear)	t <sub>WP</sub>	10	-	ns
$\overline{\text{WE}}$ Falling to End of Write (invalid output appears)	t <sub>WP1</sub>	20	-	ns
$\overline{\text{UB}}$ , $\overline{\text{LB}}$ Falling to End of Write Time <sup>1)</sup>	t <sub>BW</sub>	10	-	ns
$\overline{\text{WE}}$ Falling to Output High-Z Time	t <sub>WHZ</sub>	-	8	ns
Valid Input Data to End of Write Time	t <sub>DS</sub>	8	-	ns
End of Write to Valid Input Data Time	t <sub>DH</sub>	0	-	ns
Address Transition Time to $\overline{\text{CS}}$ falling <sup>2)</sup>	t <sub>CAS</sub>	0	-	ns
$\overline{\text{CS}}$ Rising to Address Transition Time <sup>2)</sup>	t <sub>CAH</sub>	0	-	ns
Page Address Transition to $\overline{\text{WE}}$ falling Time	t <sub>PAS</sub>	0	-	ns
$\overline{\text{WE}}$ falling to Page Address Transition Time	t <sub>PAH</sub>	10	-	ns
$\overline{\text{WE}}$ High Time for Page Write	t <sub>PWH</sub>	3	-	ns
$\overline{\text{CS}}$ High Time for Write End <sup>3)</sup>	t <sub>CSDW</sub>	180	-	ns

**Notes:**

1. Those parameters are applied for x16 I/O mode only.
2. Address except for page address
3. t<sub>WCA</sub> + t<sub>CSDW</sub> ≥ t<sub>WC</sub>

## Power On/Off Sequence

- When power-up, power-down or power-loss,  $\overline{CS}$  must follow  $V_{cc}$  to provide data protection.
- It is recommended that  $\overline{CS}$  must follow  $V_{cc}$  when  $V_{cc}$  is below  $V_{cc}(\text{minimum})$  and during  $t_{PU}$ .
- A 10K $\Omega$  pull-up resistor between  $V_{cc}$  and  $\overline{CS}$  pin is recommended.
- Normal operation must start after  $t_{PU}$ .

Figure 3 : Power-Up/Down Behavior

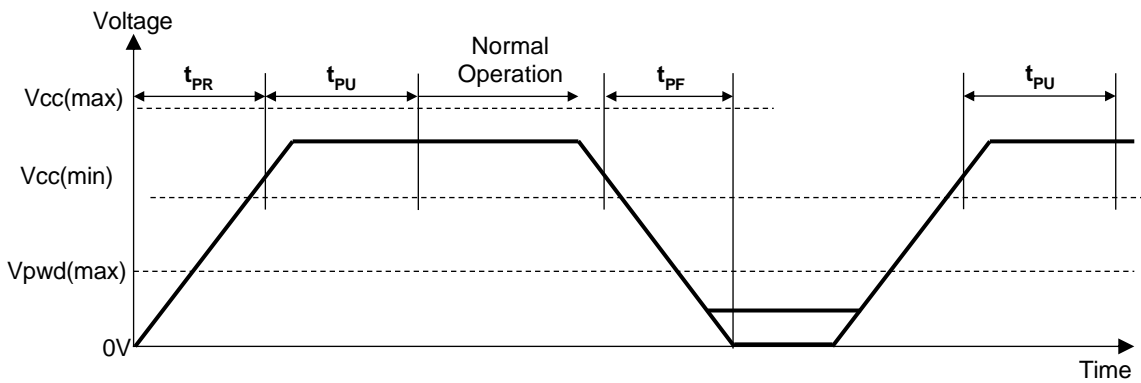


Table 16 : Power-Up/Down Timing

Parameter	Symbol	Min	Max	Units
Vcc Range	VCC	2.7	3.6	V
Vcc rising time	$t_{PR}^{(1)}$	30	-	$\mu\text{s/V}$
Vcc falling time	$t_{PF}^{(1)}$	30	-	$\mu\text{s/V}$
Vcc(min) to $\overline{CS}$ Low (first instruction) time	$t_{PU}^{(1)}$	2.0	-	ms
Vcc needed to below Vpvd for ensuring initialization will occur	$V_{PWD}^{(1)}$	-	1.6	V

**Notes:**

1: These parameters are guaranteed by characterization; not tested in production.

## Device Operation

### Read Operation: Interpage

Read operation is initiated when  $\overline{CS}$  goes to low and  $\overline{WE}$  is high. The falling edge of  $\overline{CS}$  latches the address and starts to read data from memory array. The output data are available after  $t_{CO}$ . The minimum random read cycle time is  $t_{RC}$ . The data remains in High-Z until the valid data is output.

Figure 4 : Timing Waveform of Read Cycle : x16 I/O mode

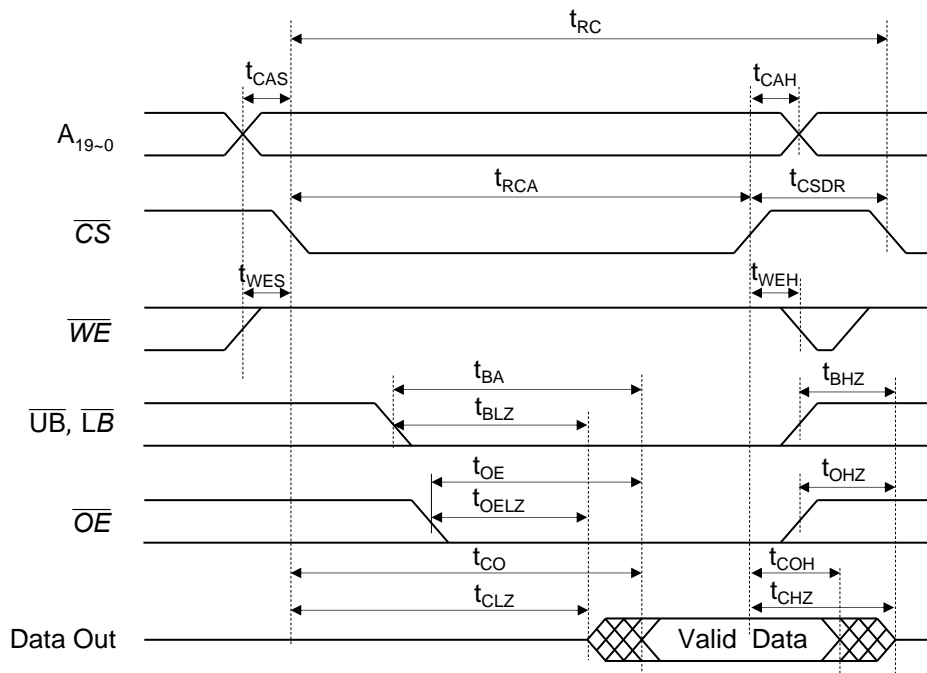
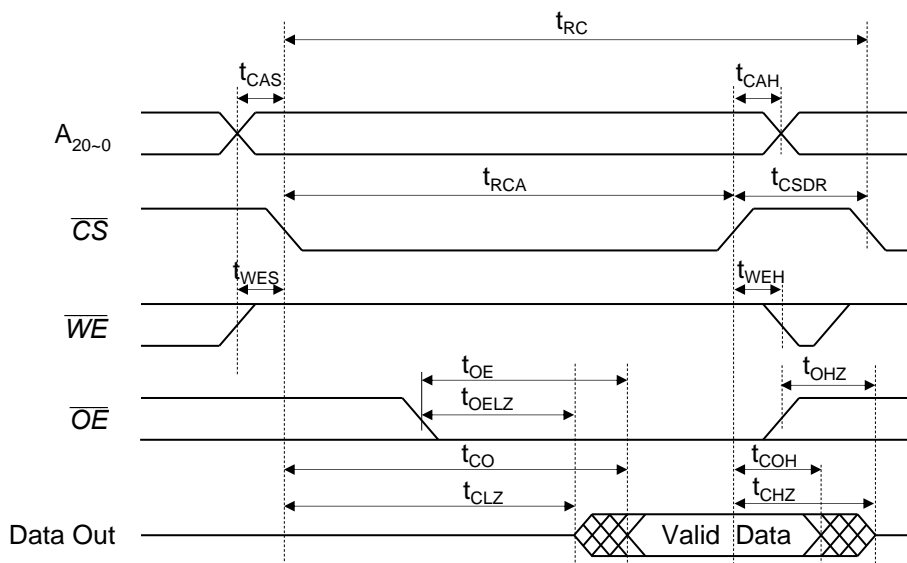


Figure 5 : Timing Waveform of Read Cycle : x8 I/O mode





## Page Mode Read Operation: Intrapage

The device supports the page mode read function to enhance the read performance. It reads a page data from memory array and latches the data into an internal page buffer.

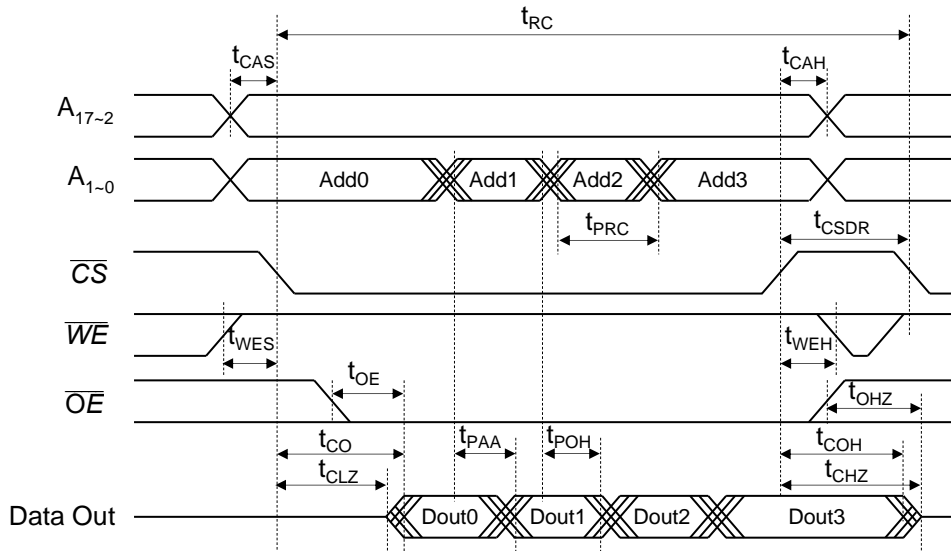
The first data is output after  $t_{CO}$ . When the next page address is input, subsequent data is output from the page buffer after  $t_{PAA}$ .

The sequence and length of page address are not restricted.

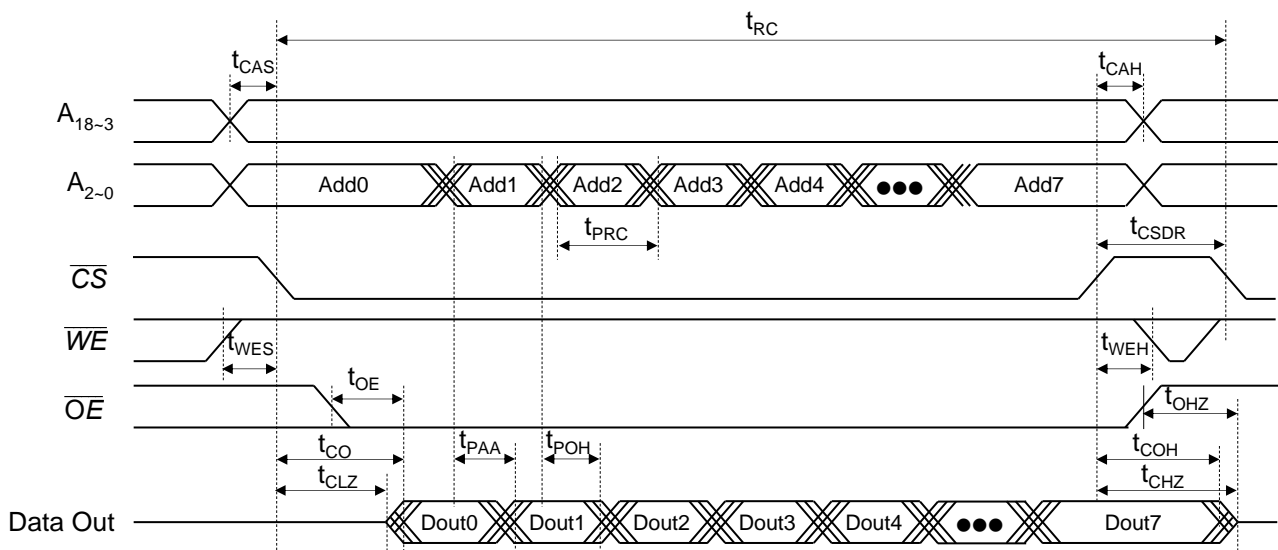
For example, the sequence A2-A0-A1 is available.

Parameter	x16 I/O mode	x8 I/O mode
Page Address	A <sub>1</sub> ~A <sub>0</sub>	A <sub>2</sub> ~A <sub>0</sub>
Page size	4-word (8-bytes)	8-word (8-bytes)

**Figure 6 : Timing Waveform of Page Mode Read Cycle : x16 I/O mode**



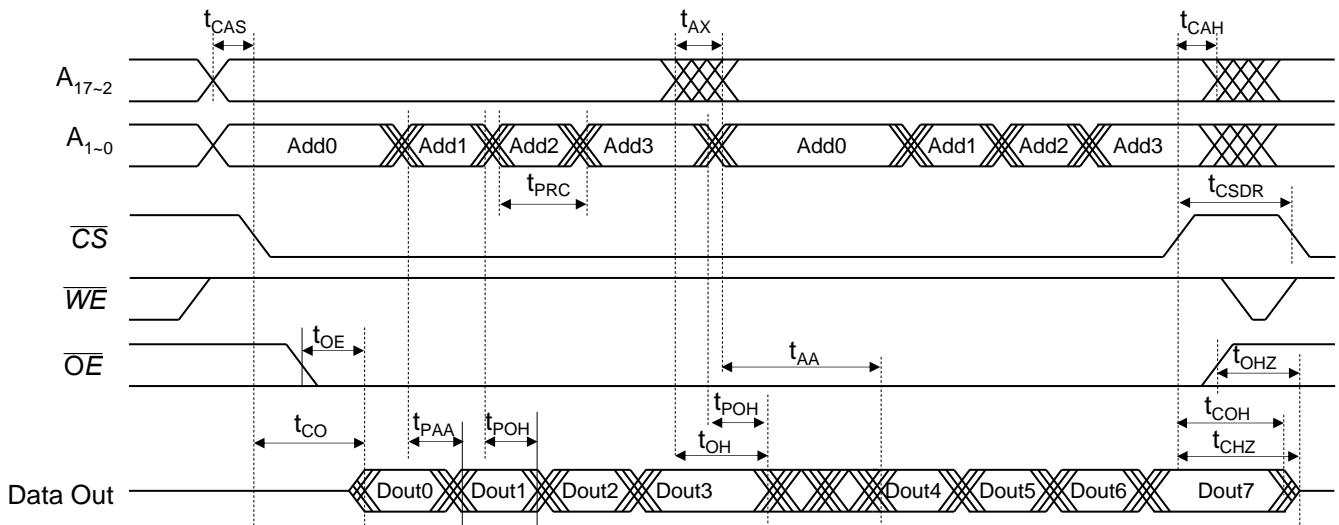
**Figure 7 : Timing Waveform of Page Mode Read Cycle : x8 I/O mode**



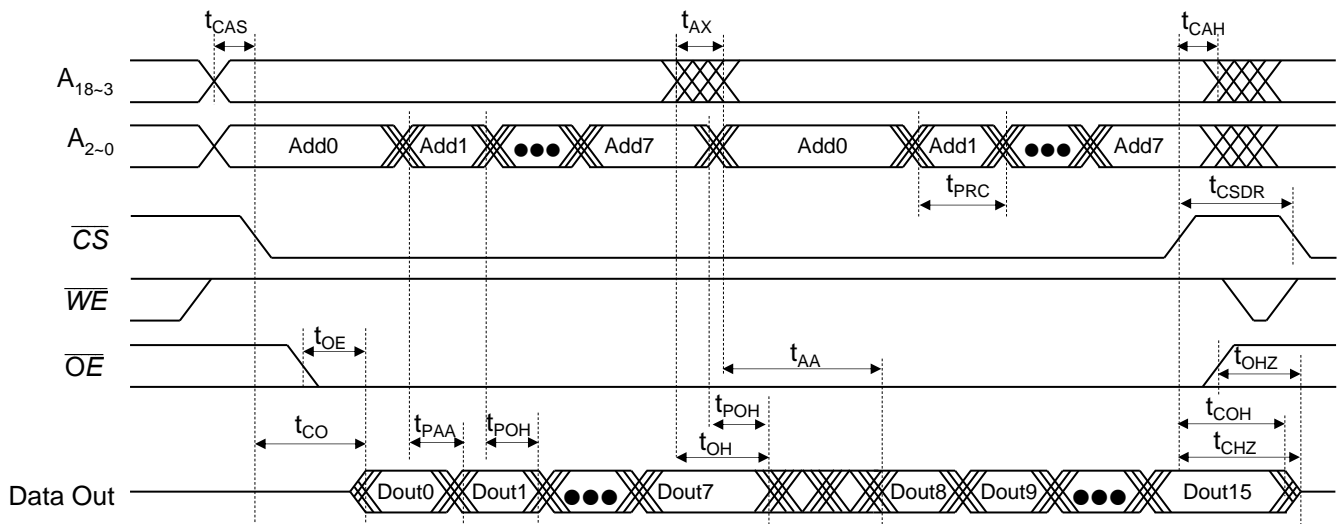
## Address Access Read Operation

During  $\overline{CS}$  is low and  $\overline{WE}$  is high, if a random address (except for the page address) are changed, the device reads a page data from memory array of a new address and latches the data into an internal page buffer. The first data is output after  $t_{AA}$ . When the next page address is input, subsequent data is output from the page buffer after  $t_{PAA}$ . The random address transition time should not exceed  $t_{AX}$ .

**Figure 8 : Timing Waveform of Address Access Read Cycle : x16 I/O mode**



**Figure 9 : Timing Waveform of Address Access Read Cycle : x8 I/O mode**



### Write Operation ( $\overline{WE}$ control): Interpage

Write operation is initiated when  $\overline{WE}$  goes to low and  $\overline{CS}$  is low. The device latches address on the falling edge of  $\overline{CS}$ . It latches the lower byte data on the rising edge of  $\overline{WE}$  or  $\overline{LB}$  and the upper byte data on the rising edge of  $\overline{WE}$  or  $\overline{UB}$  for x16 I/O mode.

It latches the data on the rising edge of  $\overline{WE}$  for x8 I/O mode. The rising edge of  $\overline{CS}$  causes the device to transfer the input data to memory array.

Figure 10 : Timing Waveform of Write Cycle ( $\overline{WE}$  control) : x16 I/O mode

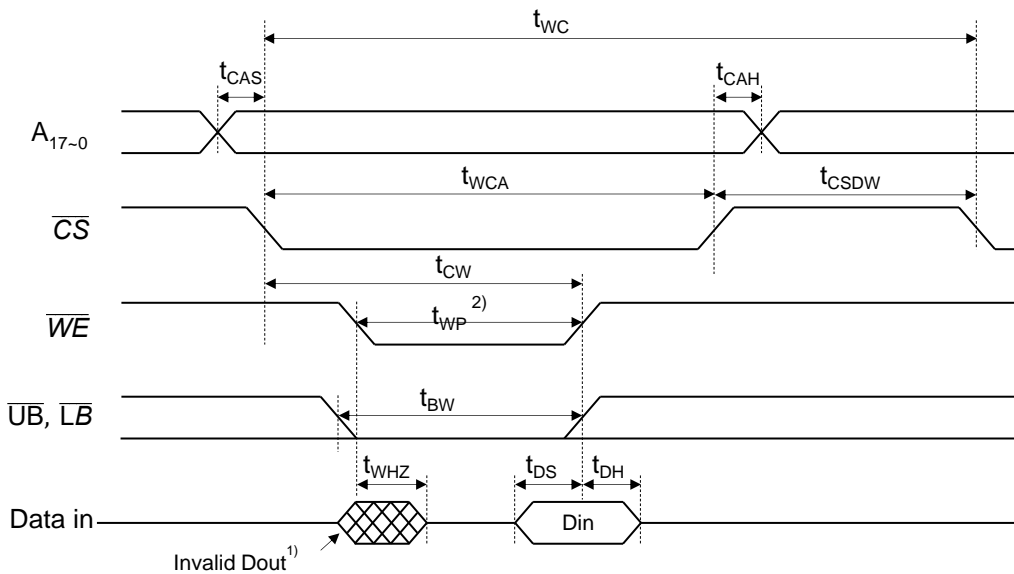
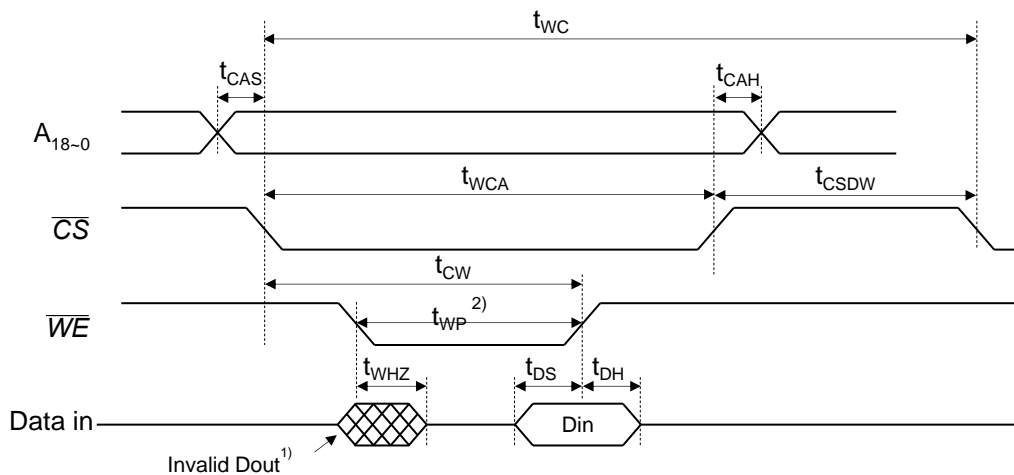


Figure 11 : Timing Waveform of Write Cycle ( $\overline{WE}$  control) : x8 I/O mode



**Notes :**

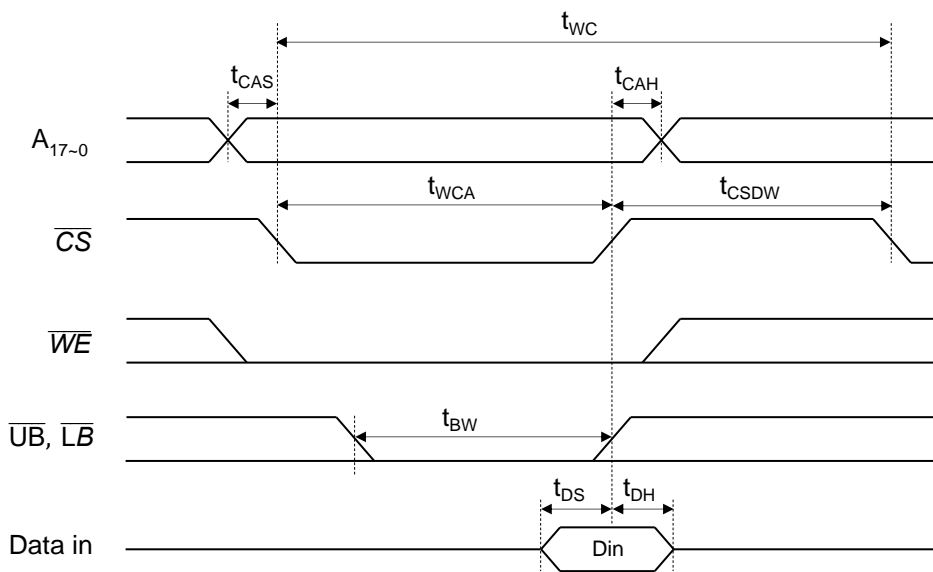
1. The data pins remain in High-Z state if the time of  $\overline{CS}$  falling to  $\overline{WE}$  falling is smaller than 30ns or  $\overline{OE}$  is High.
2. In case that the data pins do not remains in High-Z state,  $t_{WP}$  should be  $t_{WP1}$
3.  $t_{WCA} + t_{CSDW} \geq t_{WC}$

### Write Operation ( $\overline{CS}$ control): Interpage

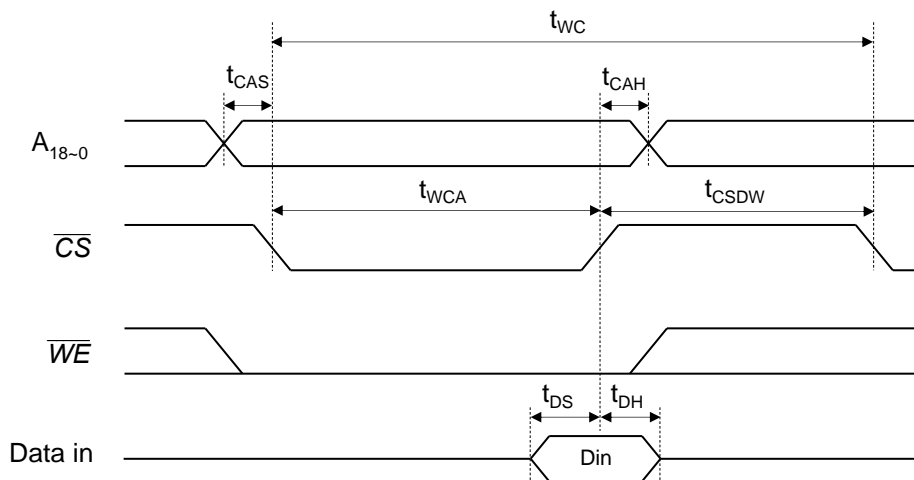
Write operation is initiated when  $\overline{CS}$  goes to low and  $\overline{WE}$  is low. The device latches address on the falling edge of  $\overline{CS}$ . It latches the lower byte data on the rising edge of  $\overline{CS}$  or  $\overline{LB}$  and the upper byte data on the rising edge of  $\overline{CS}$  or  $\overline{UB}$  for x16 I/O mode.

It latches the data on the rising edge of  $\overline{CS}$  for x8 I/O mode. The rising edge of  $\overline{CS}$  causes the device to transfer the input data to memory array.

**Figure 12 : Timing Waveform of Write Cycle ( $\overline{CS}$  control) : x16 I/O mode**



**Figure 13 : Timing Waveform of Write Cycle ( $\overline{CS}$  control) : x8 I/O mode**



### Page Mode Write Operation: Intrapage

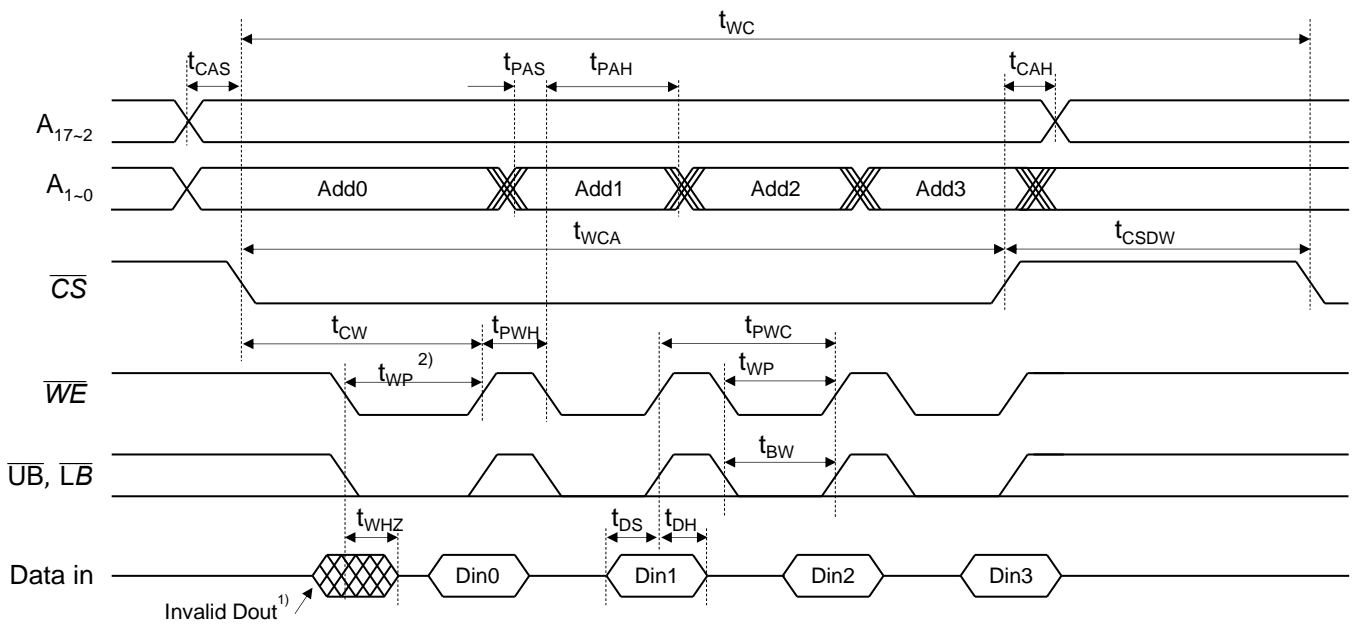
The device supports the page mode write function to enhance the write performance. It latches a page address every falling edge of  $\overline{WE}$ .

It latches the lower byte data on every rising edge of  $\overline{WE}$  or  $\overline{LB}$  and the upper byte data on every rising edge of  $\overline{WE}$  or  $\overline{UB}$  for x16 I/O mode.

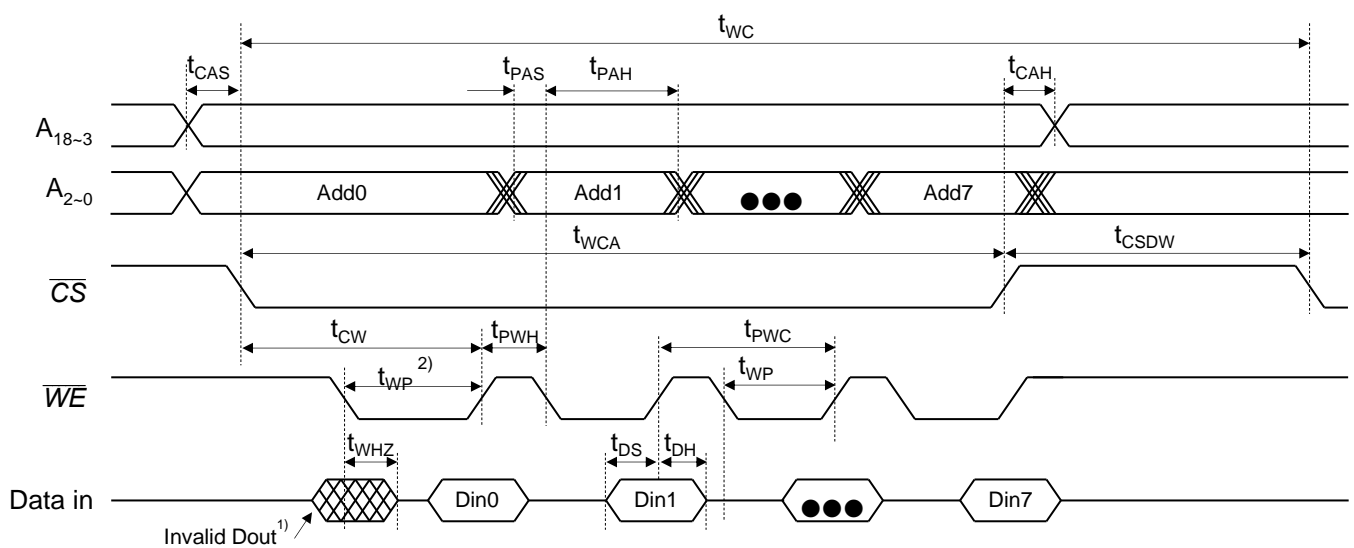
It latches the data on every rising edge of  $\overline{WE}$  for x8 I/O mode. The rising edge of  $\overline{CS}$  causes the device to transfer the input data to memory array.

The sequence and length of page address are not restricted. For example, the sequence A2-A0-A1 is available.

**Figure 14 : Timing Waveform of Page Mode Write Cycle : x16 I/O Mode**



**Figure 15 : Timing Waveform of Page Mode Write Cycle : x8 I/O Mode**



## Thermal Resistance

**Table 17 : Thermal Resistance**

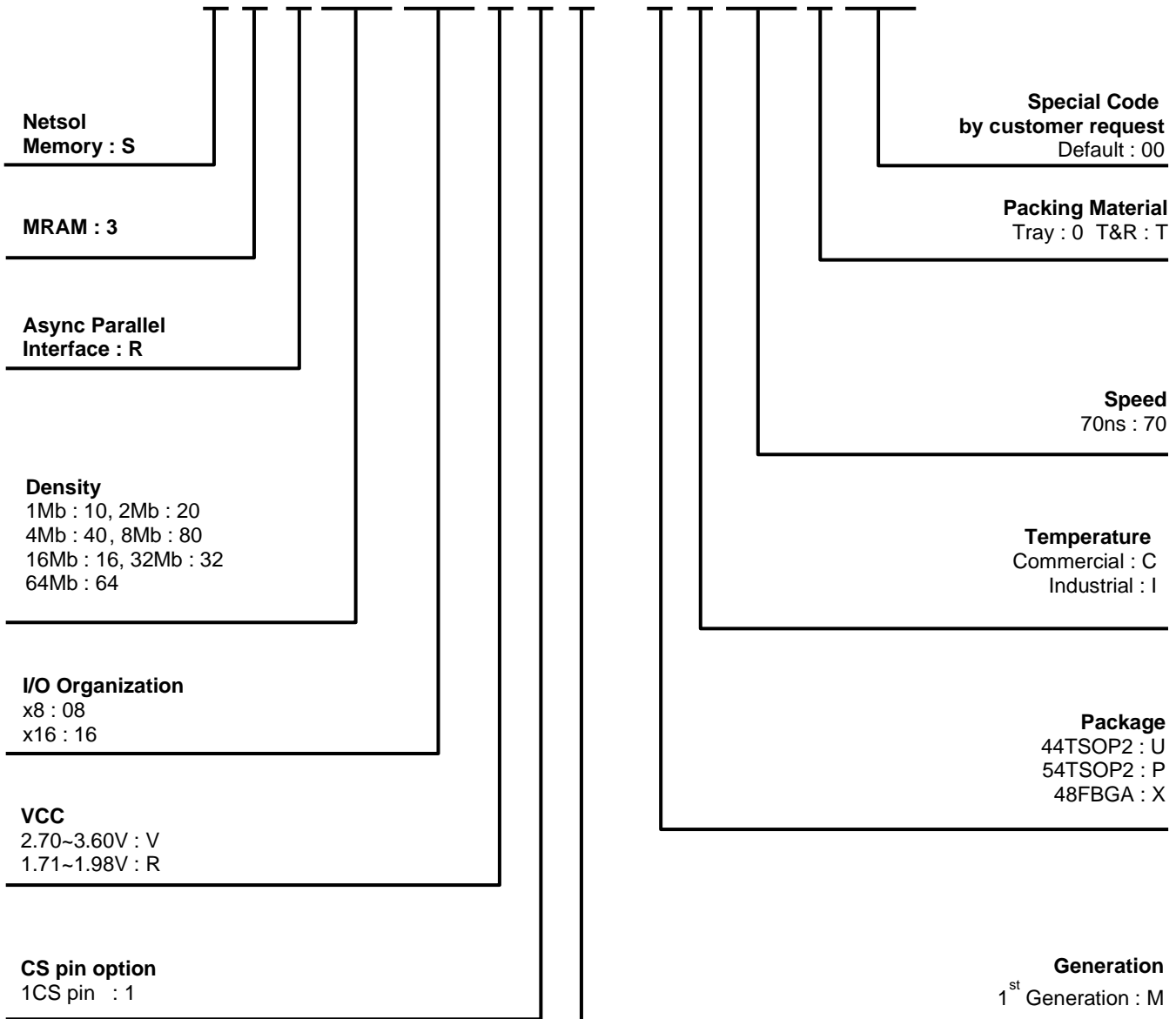
Parameter	Description	48FBGA	44TSOP2	Unit
$\theta_{JA}$	Thermal resistance (junction to ambient)	69.4	65.2	°C/W
$\theta_{JC}$	Thermal resistance (junction to case)	31.1	15.9	

**Notes:**

1: These parameters are guaranteed by characterization; not tested in production

## Part Numbering System

<b>S</b>	<b>3</b>	<b>R</b>	<b>x</b>	<b>x</b>	<b>x</b>	<b>x</b>	<b>x</b>	<b>x</b>	<b>x</b>	<b>-</b>	<b>x</b>	<b>x</b>	<b>x</b>	<b>x</b>	<b>x</b>	<b>x</b>	<b>x</b>
1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18



## Ordering Part Numbers

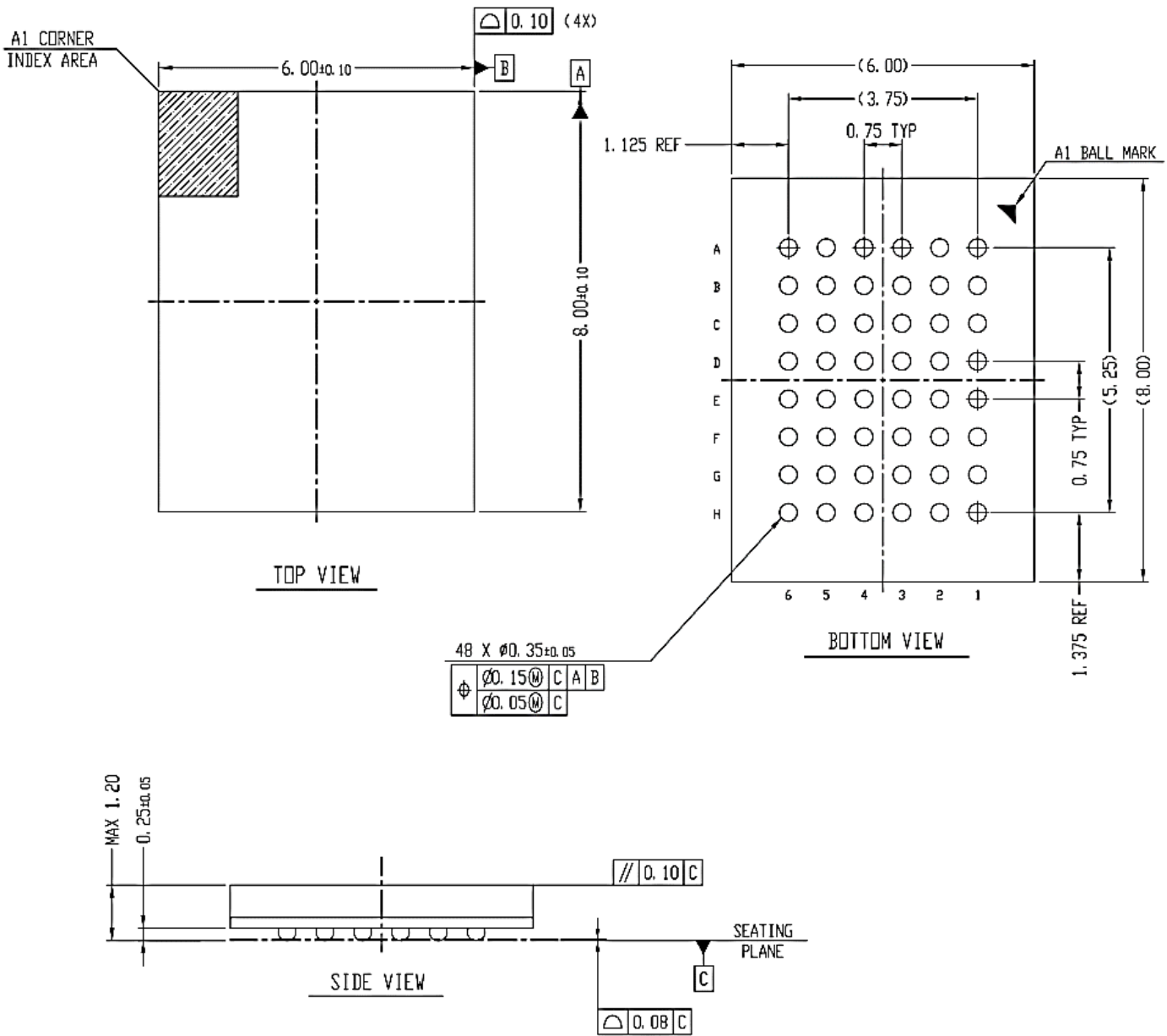
Table 18 : Ordering Part Numbers

Density	Org.	Temperature	Package	Packing Material	Part Number
4Mb	x16	-40°C ~ 85°C	44TSOP2	Tray	S3R4016V1M-UI70
				Tape and Reel	S3R4016V1M-UI70T
			48FBGA	Tray	S3R4016V1M-XI70
				Tape and Reel	S3R4016V1M-XI70T
	x8	-40°C ~ 85°C	44TSOP2	Tray	S3R4008V1M-UI70
				Tape and Reel	S3R4008V1M-UI70T
			48FBGA	Tray	S3R4008V1M-XI70
				Tape and Reel	S3R4008V1M-XI70T



# Package Dimension

## 48 FBGA



**[Notes]**

1. All Dimensions in Millimeters
2. Solder ball Diameter is post reflow diameter  
(Raw Solder ball size is  $\Phi 0.30$ mm)



## Revision History

Revision	Date	Description
0.1	Jun. 2022	Initial Release, Preliminary
0.2	Jan. 2023	1. Update the magnetic immunity parameter(Table 9) 2. Update the pin capacitance(Table 11) 3. Update thermal resistance(Table 17) 4. Change Ordering Part Numbers(Table 18) - delete commercial temperature range
1.0	Jul. 2023	1. Remove Preliminary status 2. Update DC Characteristics(Table 13)
1.1	Mar. 2024	1. Change Write Cycle Time (Table 15) - t <sub>wc</sub> 320ns → 240ns, t <sub>CSDW</sub> 250ns → 180ns
1.2	May. 2024	1. The 4Mb density data sheet has been separated from the 1Mb/2Mb/4Mb/8Mb/16Mb integrated data sheet.
1.3	Jan. 2025	1. Update the Data Retention parameter(Table 9)

\* Products and specifications discussed herein are subject to change by Netsol without notice.